

30V, 280A N-CHANNEL POWER MOSFET

GENERAL DESCRIPTION

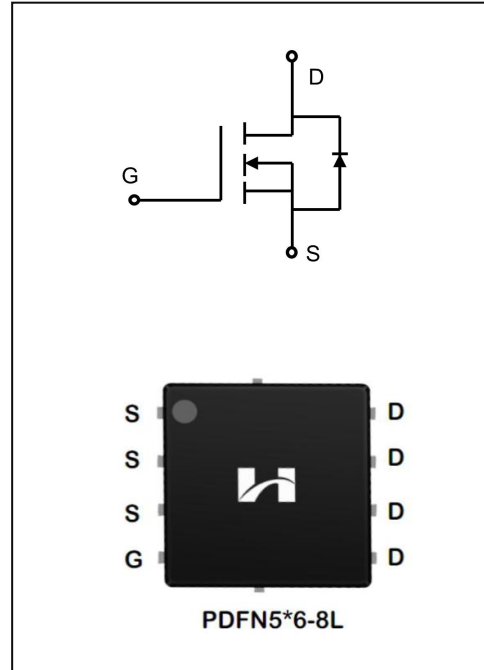
The SGM030R7T uses advanced SGT technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety of applications.

Features

- ◆  $V_{DS}=30V, I_D=280A$
- ◆  $R_{DS(on)}$   
TYP:0.55mΩ@ $V_{GS}=10V$

Applications

- ◆ Power factor correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SGM030R7T	PDFN5*6-8L	SGM030R7T	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V <sub>DS</sub>	30	V
Gate-Source Voltage		V <sub>GS</sub>	±20	
Drain Current	T <sub>C</sub> = 25°C	I <sub>D</sub>	280	A
	T <sub>C</sub> = 100°C		176	
Drain Current Pulsed(Note 1)		I <sub>DM</sub>	1120	
Power Dissipation(T <sub>C</sub> =25°C) -Derate above 25°C		P <sub>D</sub>	139	W
Single Pulsed Avalanche Energy (Note 2)		E <sub>AS</sub>	135	mJ
Operation Junction Temperature Range		T <sub>J</sub>	-55~+150	°C
Storage Temperature Range		T <sub>stg</sub>	-55~+150	
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		TL	260	

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.9	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	50	

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	B <sub>VDS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	30	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	--	--	1.0	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
On Characteristics						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	1.3	1.6	2.3	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A	--	0.55	0.7	mΩ
Dynamic Characteristics						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V, f=1.0MHZ	1	1.6	10	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V V <sub>GS</sub> =0V f=1.0MHZ	--	9043	--	pF
Output Capacitance	C <sub>oss</sub>		--	5388	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	291	--	
Switching Characteristics						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =20V, V <sub>DS</sub> =10V R <sub>G</sub> =3Ω, I <sub>D</sub> =20A (Note 3.4)	--	25	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	70	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	105	--	
Turn-off Fall Time	t <sub>f</sub>		--	30	--	ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =45A V <sub>GS</sub> =10V (Note 3.4)	--	122	--	nc
Gate-Source Charge	Q <sub>gs</sub>		--	37	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	7.7	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	280	A
Pulsed Source Current	$I_{SM}$		--	--	1120	
Diode Forward Voltage	$V_{SD}$	$I_S=20A, V_{GS}=0V$	--	0.75	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=13.5A, V_R=30V, dI_F/dt=100A/\mu S$	--	102	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	171	--	nC

1. Pulse width limited by maximum junction temperature
2.  $L=0.1mH, V_{DD}=24V, V_G=10V, R_G=25\Omega, \text{ starting } T_J=25^\circ C$
3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$
4. Essentially independent of operating temperature

Typical Performance Characteristics

Figure1.OutputCharacteristics

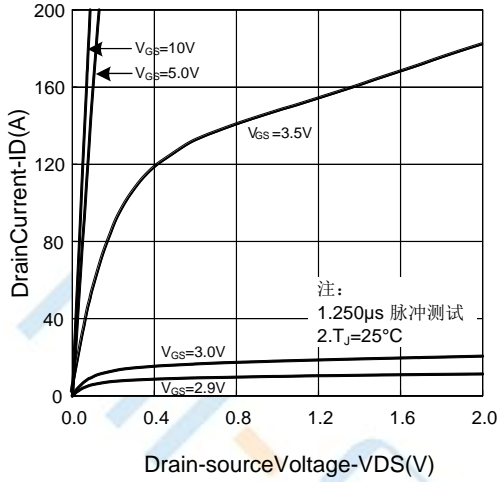


Figure2.TransferCharacteristics

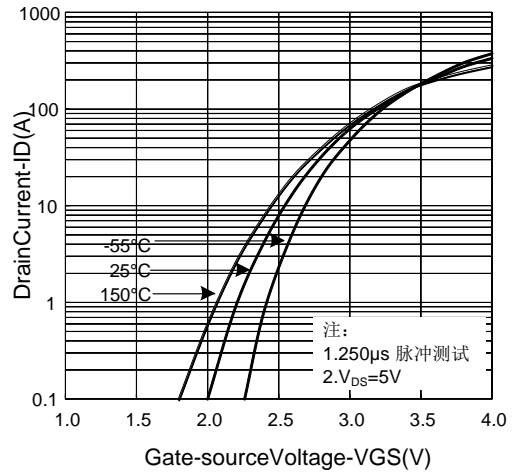


Figure3.On-resistancevs.DrainCurrent

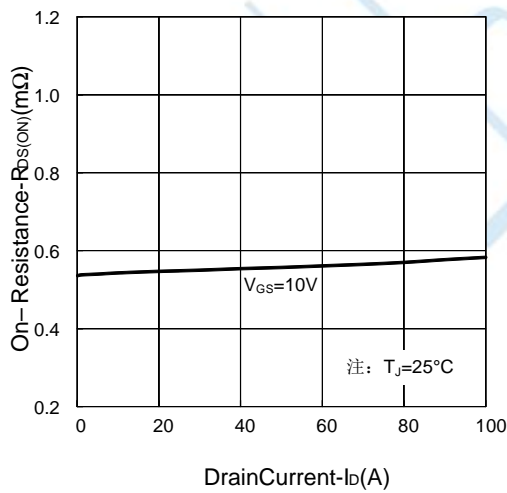


Figure4.BodyDiodeForwardVoltage Variationvs.SourceCurrentandTemperature

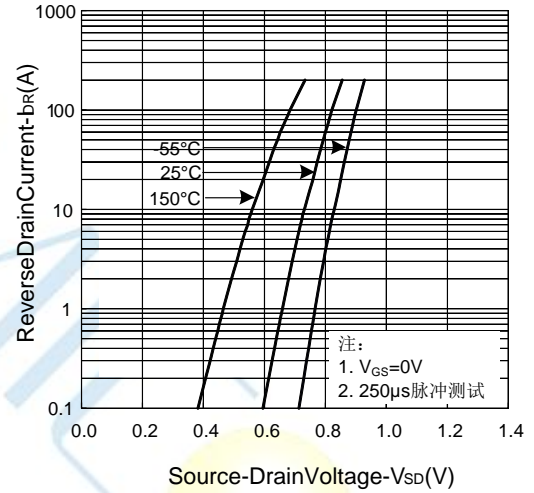


Figure5.CapacitanceCharacteristics

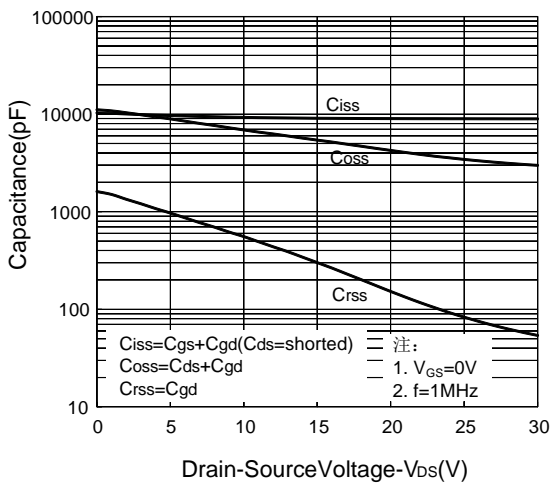
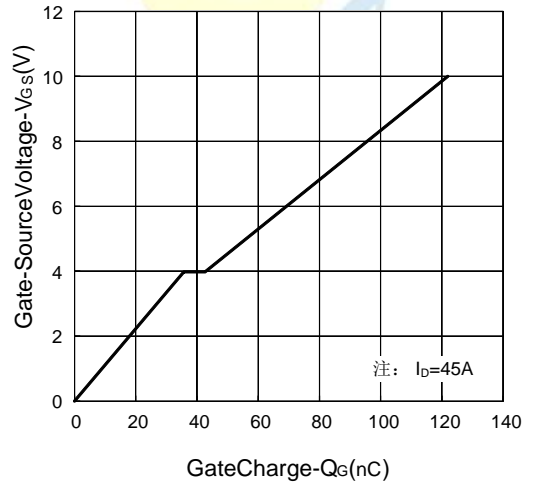


Figure6.GateCharge



Typical Performance Characteristics

Figure7. Breakdown Voltage vs. Temperature Characteristics

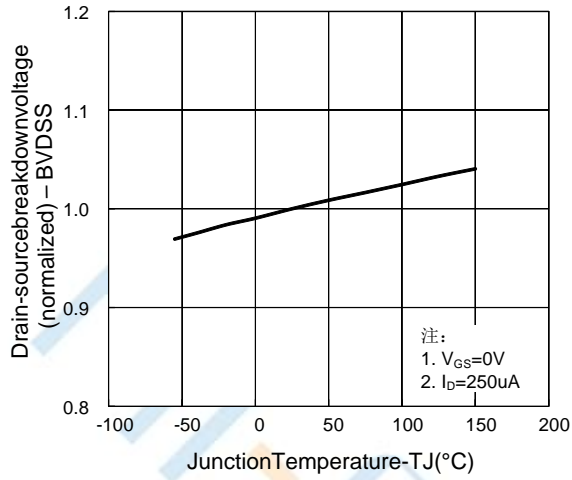


Figure8. On-resistance vs. Temperature Characteristics

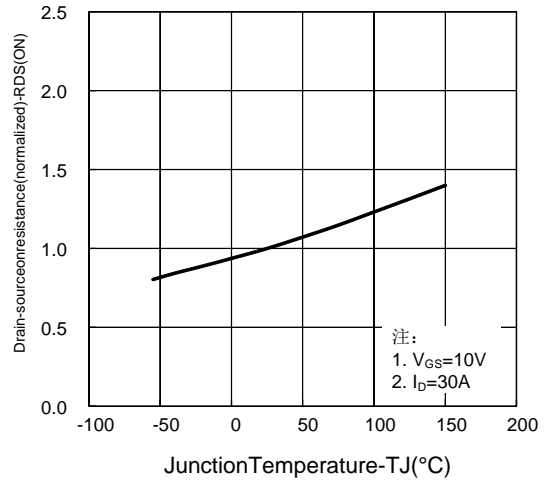
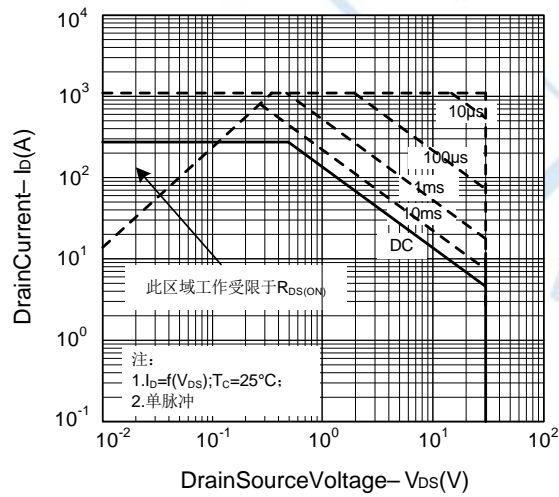
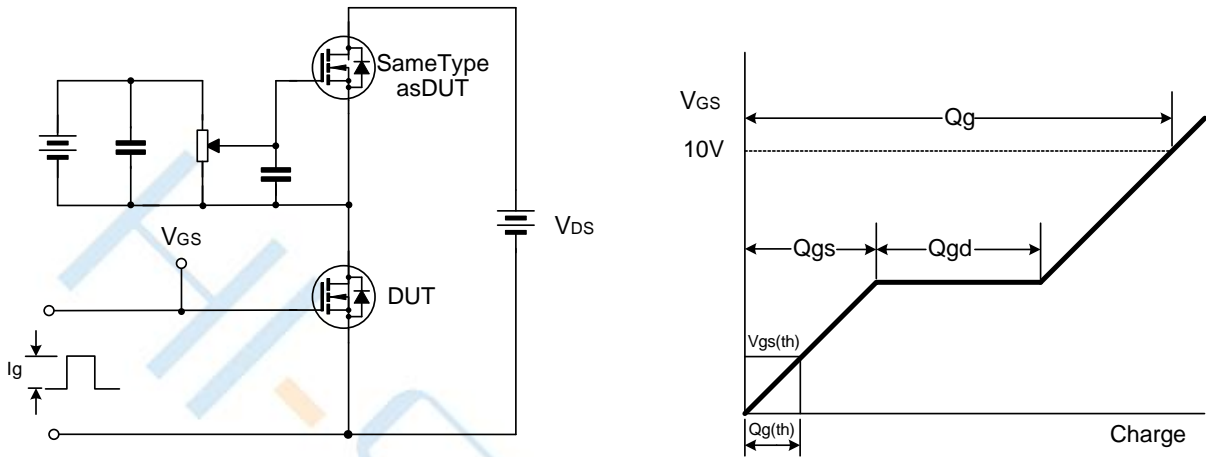


Figure9. Max. Safe Operating Area

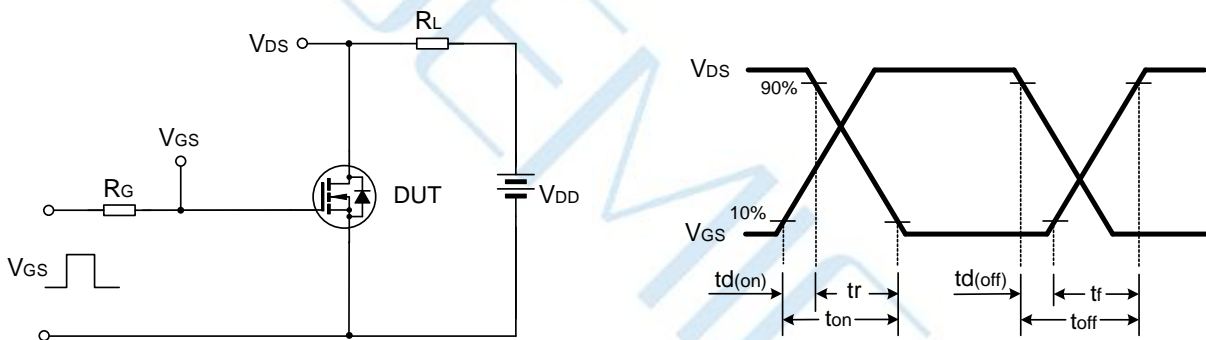


Test Circuit

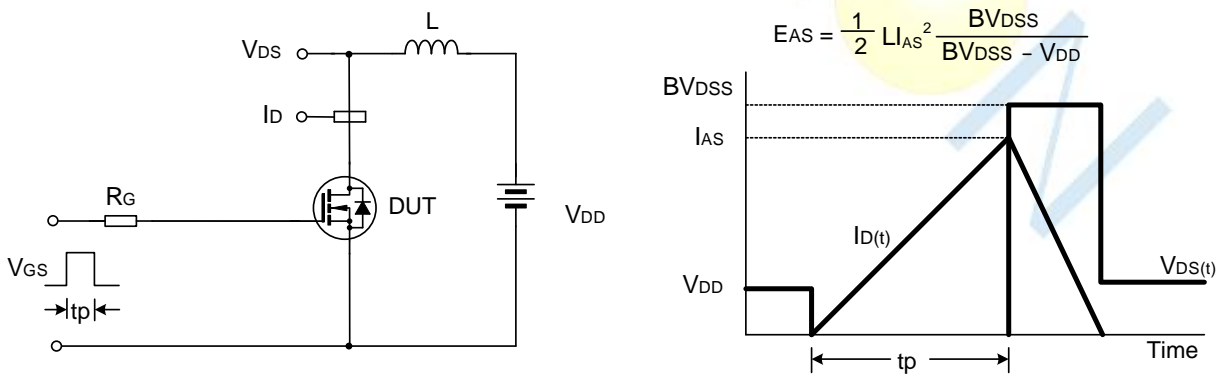
Gate Charge Test Circuit & Waveform



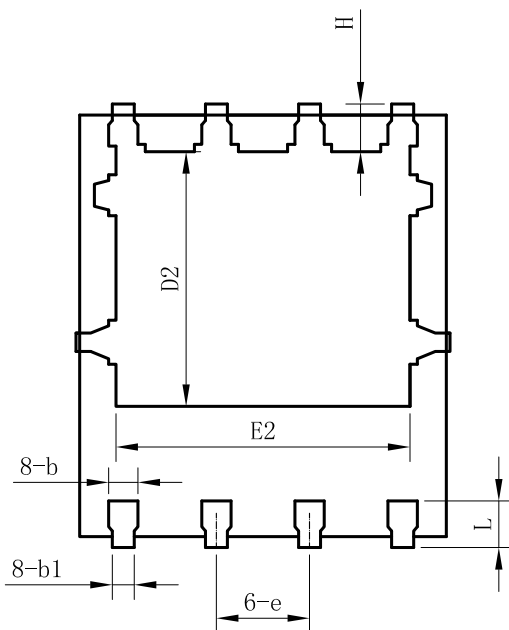
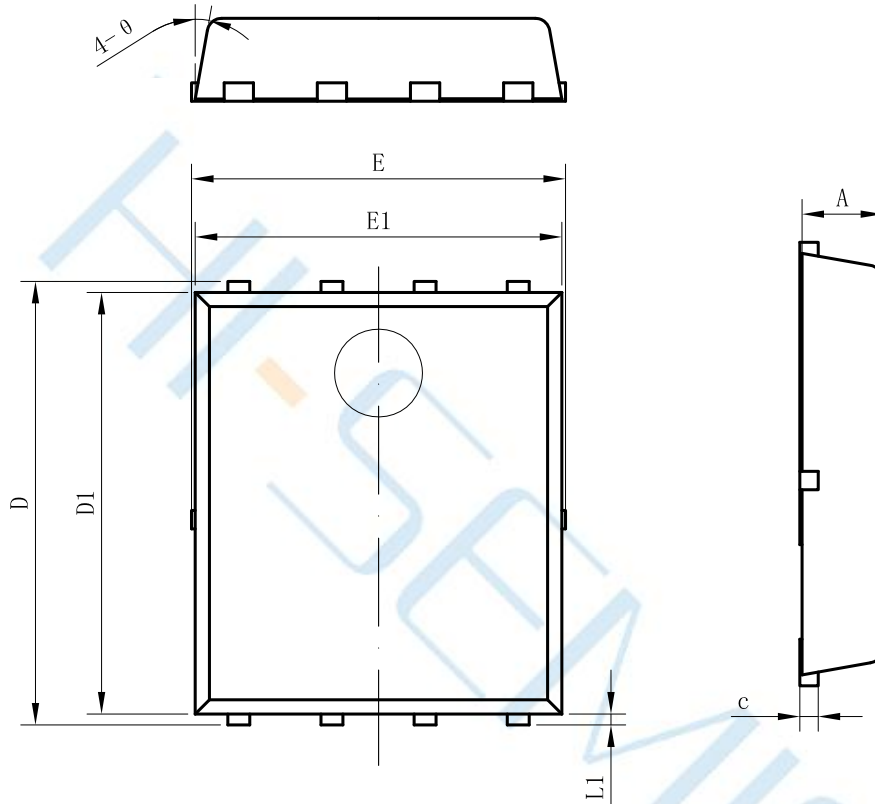
Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveform



Unit:mm



COMMON DIMENSIONS  
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	1.0	1.1	1.2
b	0.35	0.4	0.45
b1		(0.3)	
c	0.2	0.25	0.35
D	5.9	6.05	6.2
D1	5.65	5.75	5.85
D2		(3.475)	
E			5.2
E1	4.9	5	5.1
E2		(4.01)	
e		1.27BSC	
H	0.5	0.65	0.75
L	0.51	0.635	0.75
L1		0.15	
θ		10°	

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